

Notice of References Cited

Application/Control No.

10/582,853

Applicant(s)/Patent Under
Reexamination
ASANO, SEIJI

Examiner

WAE LOUIE

Art Unit

3661

Page 1 of 3

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Page 2 of 3

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	Examiner WAE LOUIE		Art Unit 3661	Page 3 of 3

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